

AN5011

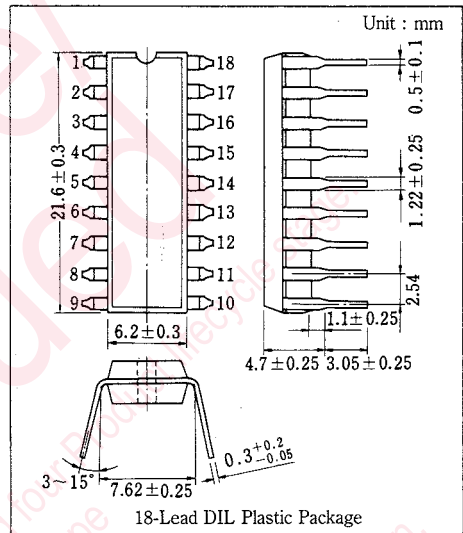
TV Electronic Channel Selection Circuit

Outline

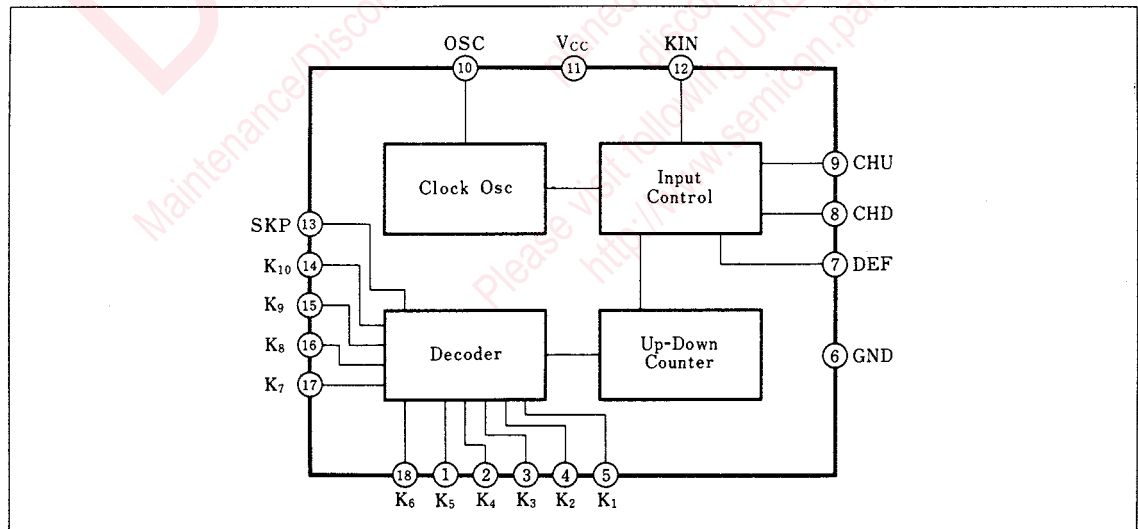
The AN5011 is an integrated circuit designed for electronic tuner circuit by the preset volume method.

Features

- Simplifies selection circuit up to 10 channels
- Incorporating clock oscillator, input control, UP-DOWN counter and decoder circuits
- Remote control system available (UP-DOWN bidirectional)
- Clock frequency changeable by external components
- Provided with pulse output
- Channel initialize when power is switched on can be set at any channel
- Selection output breakdown voltage : 40V
- Selection output saturation voltage : <math><0.15\text{V}</math> (5mA)
- Supply voltage : 6.0V
- Channel selection : 10 channels, jump over selection available



Block Diagram



■ Absolute Maximum Ratings (Ta=25°C)

Item		Symbol	Rating		Unit
Voltage	Supply Voltage	V_{CC}	7.2		V
	Circuit Voltage	V_{K-6}^{*1}	-0.5	50	V
		V_{7-6}	-0.5	14.4	V
		V_{11-6}	-0.5	7.2	V
		V_{10-6}	-0.5	7.2	V
Current	Supply Current	I_{tot}	60		mA
	Circuit Current	I_K^{*2}	-5	15	mA
		I_7	-5	15	mA
		I_8	-5	10	mA
		I_9	-5	10	mA
		I_{10}	-5	10	mA
		I_{11}	-5	60	mA
		I_{12}	-5	10	mA
I_{13}	-5	10	mA		
Power Dissipation (Ta=75°C)		P_D	450		mW
Temperature	Operating Ambient Temperature	T_{opr}	-20~+75		°C
	Storage Temperature	T_{stg}	-40~+150		°C

* 1 : K of V_K indicates pins ① to ⑤ and ⑭ to ⑰.

* 2 : K of I_K indicates pins ① to ⑤ and ⑭ to ⑰ and ratings when output is LOW level.

■ Electrical Characteristics ($V_{CC}=V_{5-3}=12V$, Ta=25°C)

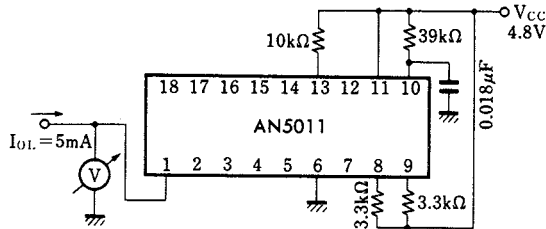
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Output Voltage Low Level (Tuning)	$V_{OL(K)}$	1	$V_{CC}=4.8V$, $I_{OL}=5mA$			0.15	V
Output Current High Level (Tuning)	$I_{OH(K)}$	2	$V_{CC}=7.2V$, $V_{OH}=35V$			5	μA
Output Voltage Low Level (DEF)	$V_{OL(D)}$	3	$V_{CC}=4.8V$, $I_{OL}=5mA$			5	V
Output Current High Level (DEF)	$I_{OH(D)}$	4	$V_{CC}=7.2V$, $V_{OH}=14.4V$			5	μA
Input Current Low Level (CHD)	$I_{IL(CHD)}$	5	$V_{CC}=7.2V$, $V_{IL}=0V$	-5			μA
Input Current Low Level (CHU)	$I_{IL(CHU)}$	7	$V_{CC}=7.2V$, $V_{IL}=0V$	-5			μA
Input Current High Level (CHD)	$I_{IH(CHD)}^{*1}$	6	$V_{CC}=4.8V$		50		μA
Input Current High Level (CHU)	$I_{IH(CHU)}^{*1}$	8	$V_{CC}=4.8V$		50		μA
Input Current Low Level (KIN)	$I_{IL(KI)}$	9	$V_{CC}=7.2V$, $V_{IL}=0V$	-10			μA
Input Current High Level (KIN)	$I_{IH(KI)}^{*2}$	10	$V_{CC}=4.8V$		200		μA
Input Current Low Level (SKP)	$I_{IL(SK)}$	11	$V_{CC}=7.2V$, $V_{IL}=0V$	-5			μA
Input Current High Level (SKP)	$I_{IH(SK)}^{*1}$	12	$V_{CC}=4.8V$		50		μA
Input Current Low Level (OSC)	$I_{IL(OS)}$	13	$V_{CC}=7.2V$, $V_{IL}=1.0V$			5	μA
Input Current High Level (OSC)	$I_{IH(OS)}$	14	$V_{CC}=4.8V$, $V_{IH}=4V$	1.7		3.2	mA
Oscillation Frequency (Clock)	fosc	15	$V_{CC}=6V$	1.5	2.0	2.5	kHz
Total Circuit Current	I_{tot}	16	$V_{CC}=6V$	23	35	50	mA

* 1 : DEF Pin (⑦) shall be "H" level (3.0V or more).

* 2 : DEF Pin (⑦) shall be "L" level (1.0V or less).

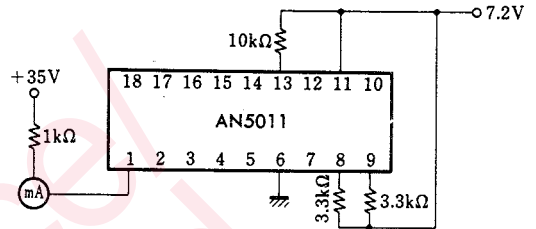
Note: Operating supply voltage is: $V_{CC} (opr) = 4.8 \sim 7.2V$.

Test Circuit 1 ($V_{OL(K)}$)



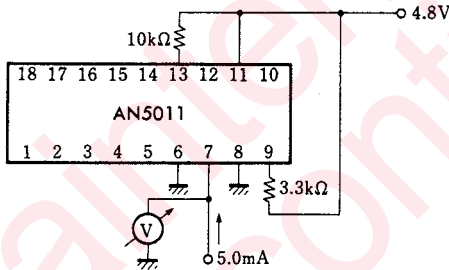
Note: Pins ① to ⑤ and ⑭ to ⑰ are used for measuring pins. First, short-circuit pins ⑫ (KIN) and ⑮ (KI) to set the measuring pin to ⑤. Then, make CHU and CHD pins "L" level to set K1 to K16 sequentially. Pins other than measuring pins are not required for connection.

Test Circuit 2 ($I_{OH(K)}$)

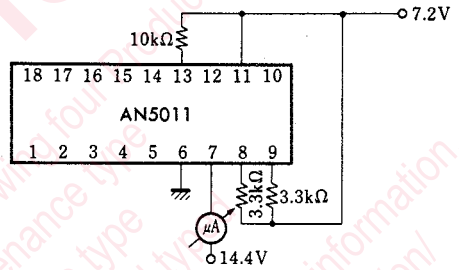


Note: Pins ① to ⑤ and ⑭ to ⑰ are used for measuring pins. Pins other than measuring pins are not required for connection.

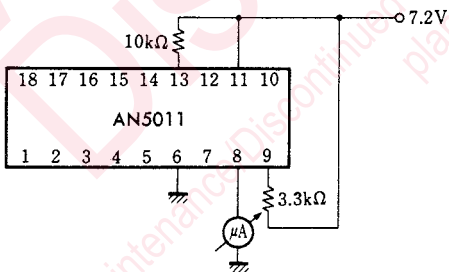
Test Circuit 3 ($V_{OL(D)}$)



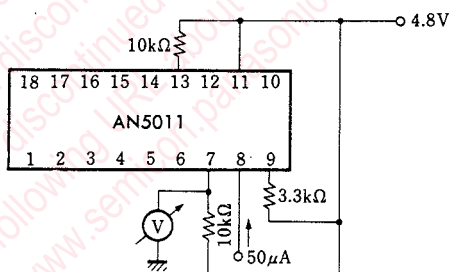
Test Circuit 4 ($I_{OH(D)}$)



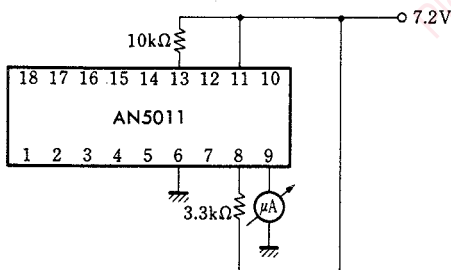
Test Circuit 5 ($I_{IL(CHD)}$)



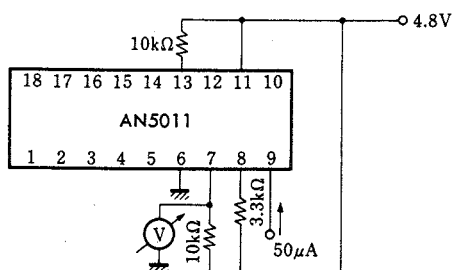
Test Circuit 6 ($I_{IH(CHD)}$)



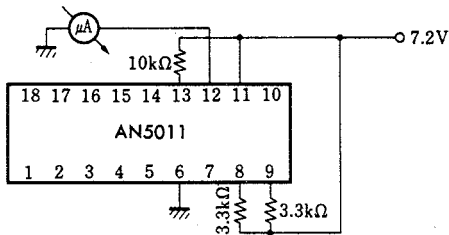
Test Circuit 7 ($I_{IL(CHU)}$)



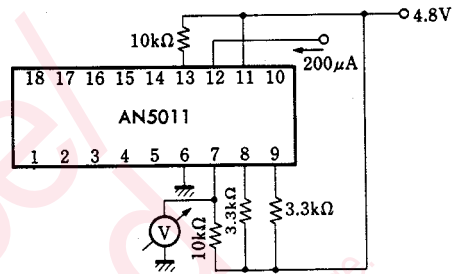
Test Circuit 8 ($I_{IH(CHU)}$)



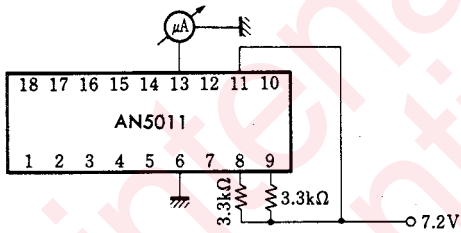
Test Circuit 9 ($I_{IL(KI)}$)



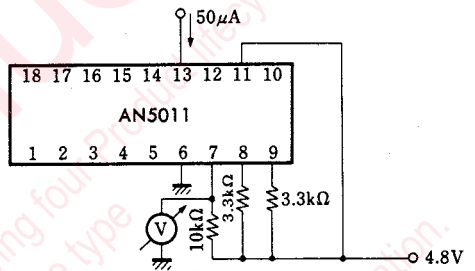
Test Circuit 10 ($I_{IH(KI)}$)



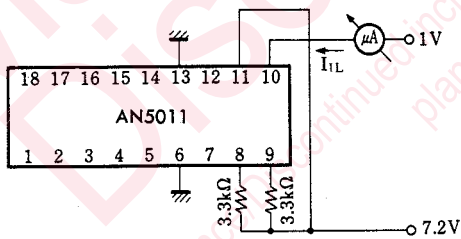
Test Circuit 11 ($I_{IL(SK)}$)



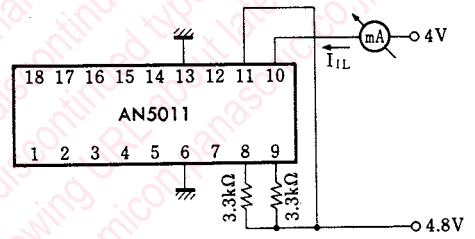
Test Circuit 12 ($I_{IH(SK)}$)



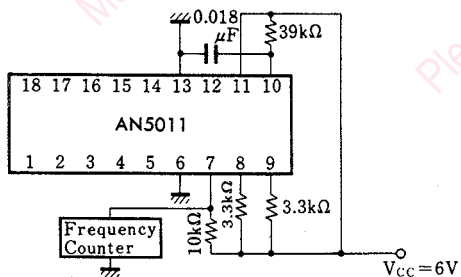
Test Circuit 13 ($I_{IL(OS)}$)



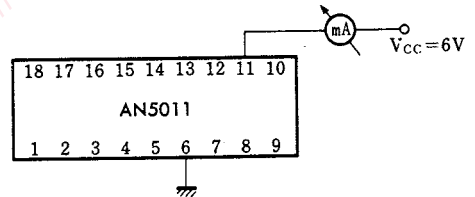
Test Circuit 14 ($I_{IH(OS)}$)



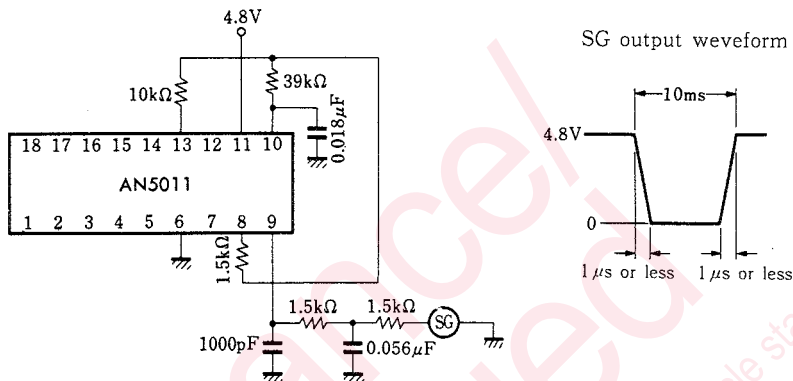
Test Circuit 15 (f_{osc})



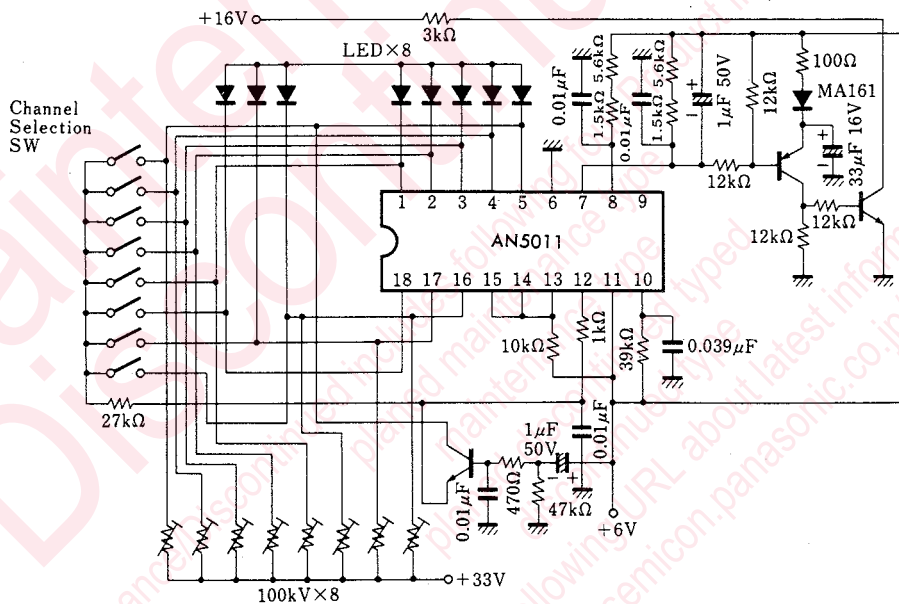
Test Circuit 16 (I_{tot})



Test Circuit 17 (sequential tuning operation by CHU and CHD inputs)



Application Circuit



Pin

Pin No.	Pin Name	Pin No.	Pin Name
1	Ch.Selection Output(5)	10	VOsc. Filter
2	Ch.Selection Output(4)	11	Vcc
3	Ch.Selection Output(3)	12	Key Input
4	Ch.Selection Output(2)	13	Skip Input
5	Ch.Selection Output(1)	14	Ch.Selection Output(10)
6	GND	15	Ch.Selection Output(9)
7	AFT Defeat Input	16	Ch.Selection Output(8)
8	Ch.Down Input	17	Ch.Selection Output(7)
9	Ch.Up Input	18	Ch.Selection Output(6)

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